

<b>Notice of References Cited</b>	Application/Control No. 10/761,009	Applicant(s)/Patent Under Reexamination JEON ET AL.	
	Examiner Long Pham	Art Unit 2814	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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